SEMICONDUCTOR INTEGRATED CIRCUIT HAVING A NUMBER OF DATA OUTPUT PINS CAPABLE OF SELECTIVELY PROVIDING OUTPUT SIGNALS AND TEST METHOD THEREOF

ABSTRACT

A semiconductor integrated circuit includes a plurality of data output pins, a data processing circuit to generate output signals responsive to an input signal, and an output selection circuit with at least a normal mode and a test mode. A first group of output signals are provided to a first group of data output pins in a first test cycle of the test mode. And a second group of output signals are provided to a second group of data output pins during a second test cycle of the test mode. The semiconductor integrated circuit can be tested by means of a test device having less test pins than the output pins of the semiconductor integrated circuit under test.